Search Notes

Application/Control No.	App	lication	on/Cor	ntrol	No.
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Applicant(s)/Patent under Reexamination

HSHIEH ET AL.

10/822,522 Examiner

Art Unit

Charles R. Kasenge

2125

SEARCHED					
Class	Subclass	Date	Examiner		
700	90	7/22/2006	СК		
	95				
	96				
	99				
	108				
	109				
	110				
705	7				
	8				
	26				
	27				
	28				
	29				
340	540				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST; terms: (semiconductor with (fabrication production manufacturing)), lot, MES, WIP, yield, (ship\$4 deliver\$3)	7/22/2006	СК
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